



Integrated Device Technology, Inc.

# HIGH-SPEED CMOS OCTAL D REGISTER (3-STATE)

## IDT54/74AHCT574

### FEATURES:

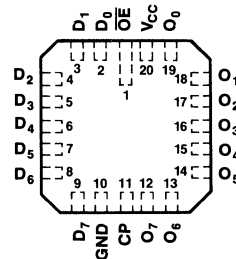
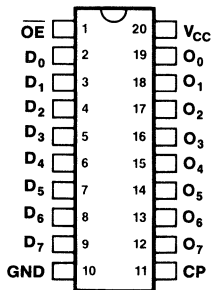
- Equivalent to ALS speeds and output drive over full temperature and voltage supply extremes
- 10ns typical address to output delay
- $I_{OL} = 14\text{mA}$  over full military temperature range
- CMOS power levels ( $5\mu\text{W}$  typ. static)
- Both CMOS and TTL output compatible
- Substantially lower input current levels than ALS ( $5\mu\text{A}$  max.)
- Octal D register (3-state)
- 100% product assurance screening to MIL-STD-883, Class B is available
- JEDEC standard pinout for DIP and LCC

### DESCRIPTION:

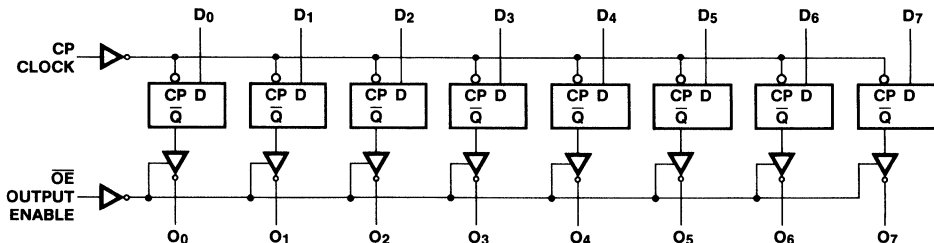
The IDT54/74AHCT574 are 8-bit registers built using advanced CEMOS™, a dual metal CMOS technology. This register consists of eight D-type flip-flops with a buffered common clock and buffered three-state output control. When the output enable ( $\overline{OE}$ ) input is LOW, the eight outputs are enabled. When the  $\overline{OE}$  input is HIGH, the outputs are in the three-state conditions.

Input data meeting the set-up and hold time requirements of the D inputs is transferred to the O outputs on the LOW-to-HIGH transition of the clock input.

### PIN CONFIGURATIONS



### FUNCTIONAL BLOCK DIAGRAM



SSD54/74AHCT374-003

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### MILITARY AND COMMERCIAL TEMPERATURE RANGES

### JULY 1986

**ABSOLUTE MAXIMUM RATING<sup>(1)</sup>**

SYMBOL	RATING	COMMERCIAL	MILITARY	UNIT
$V_{TERM}$	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
$T_A$	Operating Temperature	0 to +70	-55 to +125	°C
$T_{BIAS}$	Temperature Under Bias	-55 to +125	-65 to +135	°C
$T_{STG}$	Storage Temperature	-55 to +125	-65 to +155	°C
$I_{OUT}$	DC Output Current	120	120	mA

**NOTE:**

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

**DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE**

Following Conditions Apply Unless Otherwise Specified:

$$T_A = 0^\circ\text{C to } +70^\circ\text{C}$$

$$V_{CC} = 5.0\text{V} \pm 5\%$$

$$\text{Min.} = 4.75\text{V}$$

$$\text{Max.} = 5.25\text{V (Commercial)}$$

$$T_A = -55^\circ\text{C to } +125^\circ\text{C}$$

$$V_{CC} = 5.0\text{V} \pm 10\%$$

$$\text{Min.} = 4.50\text{V}$$

$$\text{Max.} = 5.50\text{V (Military)}$$

$$V_{LC} = 0.2\text{V}$$

$$V_{HC} = V_{CC} - 0.2\text{V}$$

SYMBOL	PARAMETER	TEST CONDITIONS <sup>(1)</sup>	MIN.	TYP. <sup>(2)</sup>	MAX.	UNIT	
$V_{IH}$	Input HIGH Level	Guaranteed Logic High Level	2.0	—	—	V	
$V_{IL}$	Input LOW Level	Guaranteed Logic Low Level	—	—	0.8	V	
$I_{IH}$	Input HIGH Current	$V_{CC} = \text{Max.}, V_{IN} = V_{CC}$	—	—	5	$\mu\text{A}$	
$I_{IL}$	Input LOW Current	$V_{CC} = \text{Max.}, V_{IN} = \text{GND}$	—	—	-5	$\mu\text{A}$	
$I_{SC}$	Short Circuit Current	$V_{CC} = \text{Max.}^{(3)}$	-60	-120	—	mA	
$V_{OH}$	Output HIGH Voltage	$V_{CC} = 3\text{V}, V_{IN} = V_{LC} \text{ or } V_{HC}, I_{OH} = -32\mu\text{A}$	$V_{HC}$	$V_{CC}$	—	V	
		$V_{CC} = \text{Min.}, V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -150\mu\text{A}$	$V_{HC}$	$V_{CC}$		—
			$I_{OH} = -1.0\text{mA MIL.}$	2.4	4.3		—
$V_{OL}$	Output LOW Voltage	$V_{CC} = 3\text{V}, V_{IN} = V_{LC} \text{ or } V_{HC}, I_{OL} = 300\mu\text{A}$	—	GND	$V_{LC}$	V	
		$V_{CC} = \text{Min.}, V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OL} = 300\mu\text{A}$	—	GND		$V_{LC}$
			$I_{OL} = 14\text{mA MIL.}$	—	—		0.4
		$I_{OL} = 24\text{mA COM'L.}$	—	—	0.5		

**NOTES:**

- For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at  $V_{CC} = 5.0\text{V}, +25^\circ\text{C}$  ambient and maximum loading.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.

**POWER SUPPLY CHARACTERISTICS**

$V_{LC} = 0.2V; V_{HC} = V_{CC} - 0.2V$

SYMBOL	PARAMETER	TEST CONDITIONS <sup>(1)</sup>		MIN.	TYP. <sup>(2)</sup>	MAX.	UNIT
$I_{CCQ}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ $V_{IN} \geq V_{HC}; V_{IN} \leq V_{LC}$ $f_{CP} = f_i = 0$		—	0.001	1.5	mA
$I_{CCT}$	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V$ <sup>(3)</sup>		—	0.5	1.6	mA
$I_{CCD}$	Dynamic Power Supply Current	$V_{CC} = \text{Max.}$ Outputs Open OE = GND One Bit Toggling 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$	—	0.15	0.25	mA/ MHz
$I_{CC}$	Total Power Supply <sup>(4)</sup> Current	$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 1.0\text{MHz}$ 50% Duty Cycle OE = GND One Bit Toggling at $f_i = 500\text{kHz}$ 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT)	—	0.15	1.8	mA
		$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 1.0\text{MHz}$ 50% Duty Cycle OE = GND Eight Bits Toggling at $f_i = 250\text{kHz}$ 50% Duty Cycle	$V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$	—	0.65	3.4	
		$V_{CC} = \text{Max.}$ Outputs Open $f_{CP} = 1.0\text{MHz}$ 50% Duty Cycle OE = GND Eight Bits Toggling at $f_i = 250\text{kHz}$ 50% Duty Cycle	$V_{IN} \geq V_{HC}$ $V_{IN} \leq V_{LC}$ (AHCT)	—	0.63	2.2	
			$V_{IN} = 3.4V$ or $V_{IN} = \text{GND}$	—	2.88	9.4	

**NOTES:**

1. For conditions shown as max. or min., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at  $V_{CC} = 5.0V$ , +25°C ambient and maximum loading.

3. Per TTL driven input ( $V_{IN} = 3.4V$ ); all other inputs at  $V_{CC}$  or GND.

4.  $I_{CC} = I_{\text{QUIESCENT}} + I_{\text{INPUTS}} + I_{\text{DYNAMIC}}$

$$I_{CC} = I_{CCQ} + I_{CCT}D_HN_T + I_{CCD}(f_{CP}/2 + f_iN_i)$$

$I_{CCQ}$  = Quiescent Current

$I_{CCT}$  = Power Supply Current for a TTL High Input ( $V_{IN} = 3.4V$ )

$D_H$  = Duty Cycle for TTL Inputs High

$N_T$  = Number of TTL Inputs at  $D_H$

$I_{CCD}$  = Dynamic Current caused by an Input Transition pair (HLH or LHL)

$f_{CP}$  = Clock Frequency for Register Devices (Zero for Non-Register Devices)

$f_i$  = Input Frequency





$N_i$  = Number of Inputs at  $f_i$

All currents are in milliamps and all frequencies are in megahertz.

**DEFINITION OF FUNCTIONAL TERMS**

PIN NAMES	DESCRIPTION
D <sub>i</sub>	The D flip-flop data inputs.
CP	Clock Pulse for the register. Enters data on the LOW-to-HIGH transition.
O <sub>i</sub>	The register three-state outputs.
$\overline{OE}$	Output Control. An active-LOW three-state control used to enable the outputs. A HIGH level input forces the outputs to the high impedance (off) state.

**TRUTH TABLE**

FUNCTION	INPUTS			OUTPUTS	INTERNAL
	$\overline{OE}$	CLOCK	D <sub>i</sub>	O <sub>i</sub>	Q <sub>i</sub>
Hi-Z	H	L	X	Z	NC
	H	H	X	Z	NC
LOAD REGISTER	L		L	L	L
	L		H	H	H
	H		L	Z	L
	H		H	Z	H

H = HIGH  
 L = LOW  
 X = Don't Care  
 Z = High Impedance  
 = LOW-to-HIGH transition  
 NC = No Change

**SWITCHING CHARACTERISTICS OVER OPERATING RANGE**

SYMBOL	PARAMETER	CONDITION	TYPICAL	COMMERCIAL		MILITARY		UNITS
				MIN.	MAX.	MIN.	MAX.	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay CP to O <sub>N</sub>	C <sub>L</sub> = 50 pf R <sub>L</sub> = 500 Ω	10.0	4.0	14.0	4.0	15.0	ns
t <sub>ZH</sub> t <sub>ZL</sub>	Output Enable Time		11.0	4.0	18.0	4.0	21.0	ns
t <sub>HZ</sub> t <sub>LZ</sub>	Output Disable Time		9.0	2.0	12.0	2.0	15.0	ns
t <sub>S</sub>	Setup Time HIGH or LOW D <sub>N</sub> to CP		2.0	15.0	—	15.0	—	ns
t <sub>H</sub>	Hold Time HIGH or LOW D <sub>N</sub> to CP		0.5	4.0	—	4.0	—	ns
t <sub>w</sub>	CP Pulse Width HIGH or LOW		10.0	14.0	—	16.5	—	ns